Claims

- 1. A material for chemical vapor deposition comprising a precursor composed of a metal compound, wherein the material contains 100 or less particles having a size of 0.5 µm or more in 1 ml, in particle measurement by a light scattering type submerged particle detector in a liquid phase.
- The material for chemical vapor deposition according to claim 1, wherein the number of particles having a size of 0.3 μm or more is 100 or less in 1 ml, in particle measurement by a light scattering type submerged particle detector.
- The material for chemical vapor deposition according to claim 1 or 2, wherein the
 number of particles having a size of 0.2 μm or more is 1000 or less in 1 ml, in particle
 measurement by a light scattering type submerged particle detector.
 - 4. The material for chemical vapor deposition according to claim 3, wherein the number of particles having a size of 0.2 μm or more is 100 or less in 1 ml, in particle measurement by a light scattering type submerged particle detector.
- 5. The material for chemical vapor deposition according to any one of claims 1 to 4, wherein the precursor is composed of a metal compound having a structure wherein the group represented by general formula (I) shown below bonds to the metal atom:

$$\begin{array}{c}
R^1 \\
-X \\
-R^2
\end{array}$$

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wherein X represents an oxygen atom or a nitrogen atom; n represents 0 when X is an oxygen atom or n represents 1 when X is a nitrogen atom; R¹ represents an organic group having 1 to 10 carbon atoms; and R² represents a hydrogen atom or an organic group having 1 to 10 carbon atoms.

- 6. The material for chemical vapor deposition according to any one of claims 1 to 4, wherein the precursor is composed of a metal compound having a structure wherein the group represented by general formula (II) shown below bonds to the metal atom:
- ——R³ (II)
 wherein R³ represents an alkyl group having 1 to 8 carbon atoms or a cyclopentadienyl group
 having 1 to 10 carbon atoms.
 - 7. The material for chemical vapor deposition according to any one of claims 1 to 6, wherein the metal compound is selected from an aluminum compound, a titanium compound, a zirconium compound, a hafnium compound, a tantalum compound, and a niobium compound.
- 10 8. The material for chemical vapor deposition according to claim 7, wherein the metal compound is a hafnium compound.
 - 9. The material for chemical vapor deposition according to any one of claims 1 to 8, which is delivered or fed in a liquid phase.
- 10. A method for forming metal-containing thin films by chemical vapor deposition
 process using the material for chemical vapor deposition according to any one of claims 1 to
 9.